



Applied Physics, Inc.

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Nano Particle Technology

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PSL Calibration Wafer Standard: 60nm to 5µm

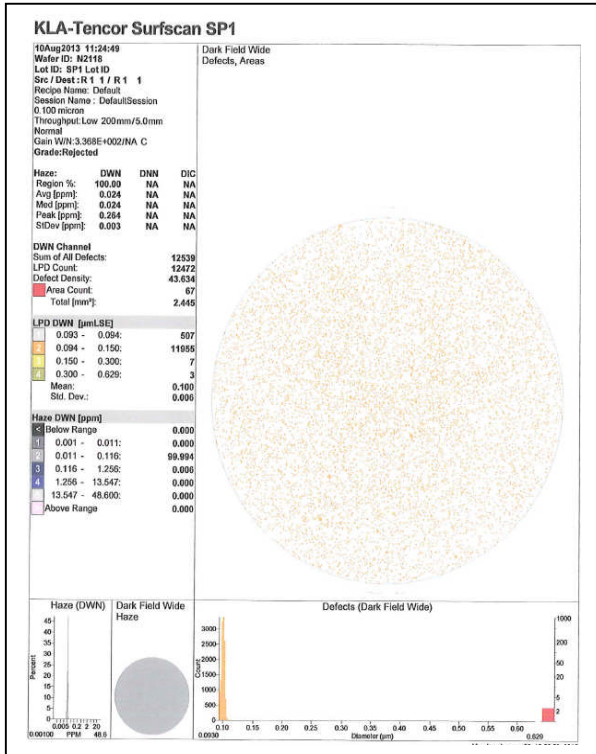
Spot Depositions from 60nm to 5µm

Full Deposition: 60nm to 10µm

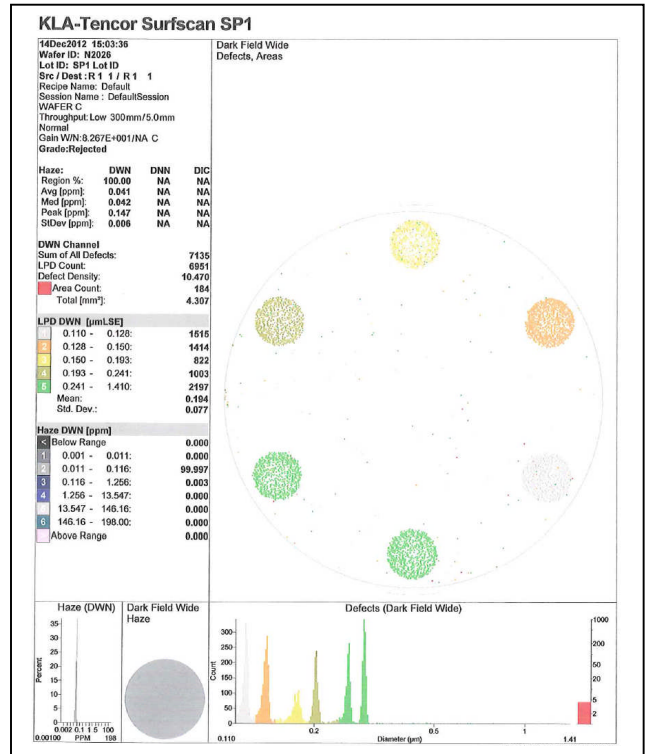
NIST Traceable, PSL Wafer Size Standards and FILM Wafer Size Standards

100mm, 125mm, 150mm, 200mm, 300mm and 450mm Prime Silicon Wafers and FILM Wafers

KLA-Tencor SPI Scans



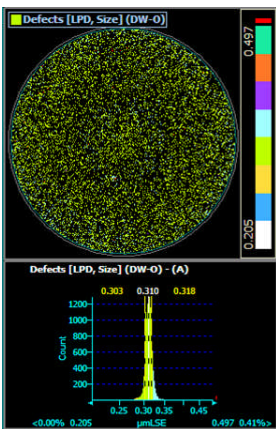
200mm, FULL DEP: 0.102µm



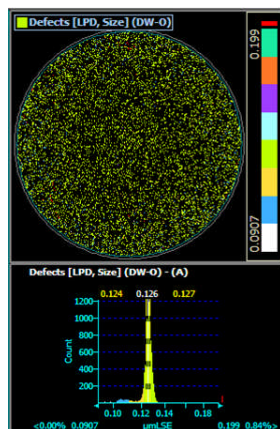
300mm, SPOT DEP: 125nm, 147nm, 204nm, 304nm, 350nm

PSL Calibration Wafer Standard includes:

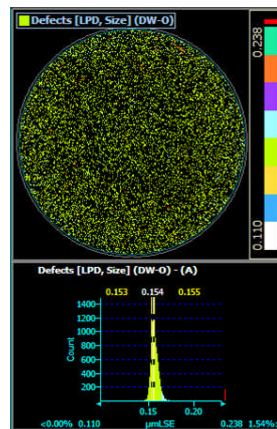
- 1) NIST Traceable, PSL Size Depositions on Prime Silicon
- 2) 200mm/300mm Wafer Scan on KLA-Tencor SP1 or SP5, ≤ 150mm Wafer Scan on Tencor 6200, color printout
- 3) Packaged in single Wafer Carrier, double bagged for shipping protection and cleanliness
- 4) NIST Traceable, Size Certification includes wafer Serial Number and deposition specifications
- 5) Optional TFF Data File, Excel Format, X/Y coordinate particle locations referenced to Notch, 200mm, 300mm wafers



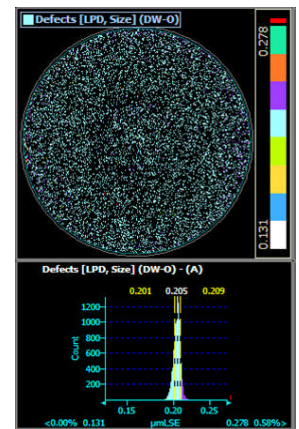
SSIS calibration at 304nm



SSIS calibration at 126nm



SSIS calibration at 155nm



SSIS calibration at 204nm

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